July 1996



SEMICONDUCTOR TM

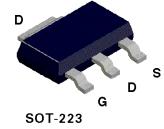
NDT455N N-Channel Enhancement Mode Field Effect Transistor

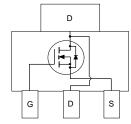
General Description

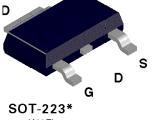
These N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

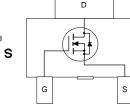
Features

- 11.5 A, 30 V. $R_{DS(ON)} = 0.015 \Omega @ V_{GS} = 10 V$ $R_{DS(ON)} = 0.02 \Omega @ V_{GS} = 4.5 V.$
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.









(J23Z)

Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter Drain-Source Voltage		NDT455N	Units	
V _{DSS}			30	V	
V _{GSS}	Gate-Source Voltage		20	V	
I _D	Drain Current - Continuous	(Note 1a)	± 11.5	A	
	- Pulsed		±40		
P _D	Maximum Power Dissipation	(Note 1a)	3	W	
		(Note 1b)	1.3		
		(Note 1c)	1.1		
Г _Ј ,Т _{STG}	Operating and Storage Temperature Range		-65 to 150	°C	
THERMA	L CHARACTERISTICS				
۲ _{өла}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°C/W	
۲ _{өлс}	Thermal Resistance, Junction-to-Case	(Note 1)	12	°C/W	

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS				•		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		30			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$				1	μA
			T _J = 55°C			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$		1	1.5	3	V
			T _J = 125°C	0.7	0.9	2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 11.5 \text{ A}$			0.013	0.015	Ω
			T _J = 125°C		0.019	0.03	
		$V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$			0.018	0.02	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		30			Α
		$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		15			
g _{FS}	Forward Transconductance	$V_{GS} = 10 \text{ V}, I_{D} = 11.5 \text{ A}$			26		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 15, V_{GS} = 0 V,$ f = 1.0 MHz			1220		pF
C _{oss}	Output Capacitance				715		pF
C _{rss}	Reverse Transfer Capacitance				280		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 15 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GEN} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			11	20	ns
ţ,	Turn - On Rise Time				16	30	ns
t _{D(off)}	Turn - Off Delay Time				48	80	ns
t _r	Turn - Off Fall Time				40	70	ns
Q _g	Total Gate Charge	$V_{DS} = 10 V,$ $I_{D} = 11.5 A, V_{GS} = 10 V$			43	61	nC
Q _{gs}	Gate-Source Charge				4		nC
Q_{gd}	Gate-Drain Charge				11		nC

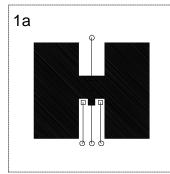
Electrical Characteristics (T _A = 25°C unless otherwise noted)							
Symbol	Parameter	Conditions	Min	Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
I _s	Maximum Continuous Drain-Source Diode Forward Current				2.5	А	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0$ V, $I_{S} = 2.5$ A (Note 2)		0.845	1.2	V	
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, \text{ I}_{\text{F}} = 2.5 \text{ A} \text{ dI}_{\text{F}}/\text{dt} = 100 \text{ A}/\mu\text{s}$			140	ns	

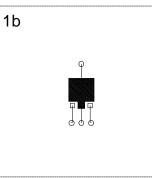
Notes: 1. $P_D(t) = \frac{T_J - T_A}{R_{\theta JA}(t)} = \frac{T_J - T_A}{R_{\theta JA}(t)} = I_D^2(t) \times R_{DS(ON) \oplus T_J}$ R_{$\theta JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{<math>\theta JC}$ is guaranteed by design while R_{$\theta CA} is defined by users. For general reference: Applications on 4.5*x5* FR-4 PCB under still air environment, typical</sub>$ </sub></sub>

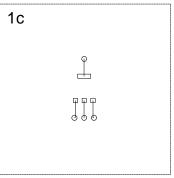
a. 42°C/W with 1 in² of 2 oz copper mounting pad.

b. 95°C/W with 0.066 in² of 2 oz copper mounting pad.

c. 110°C/W with 0.0123 in² of 2 oz copper mounting pad.

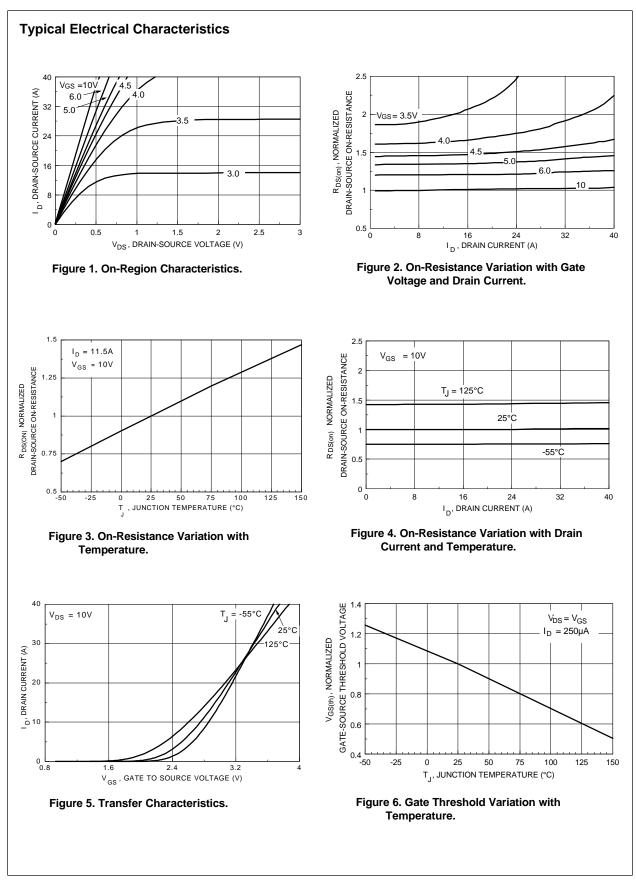




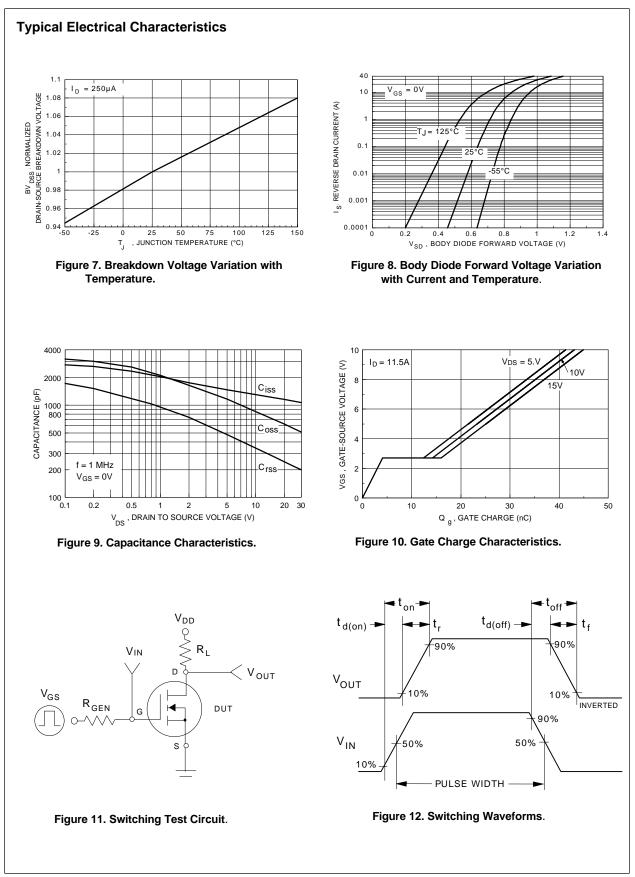


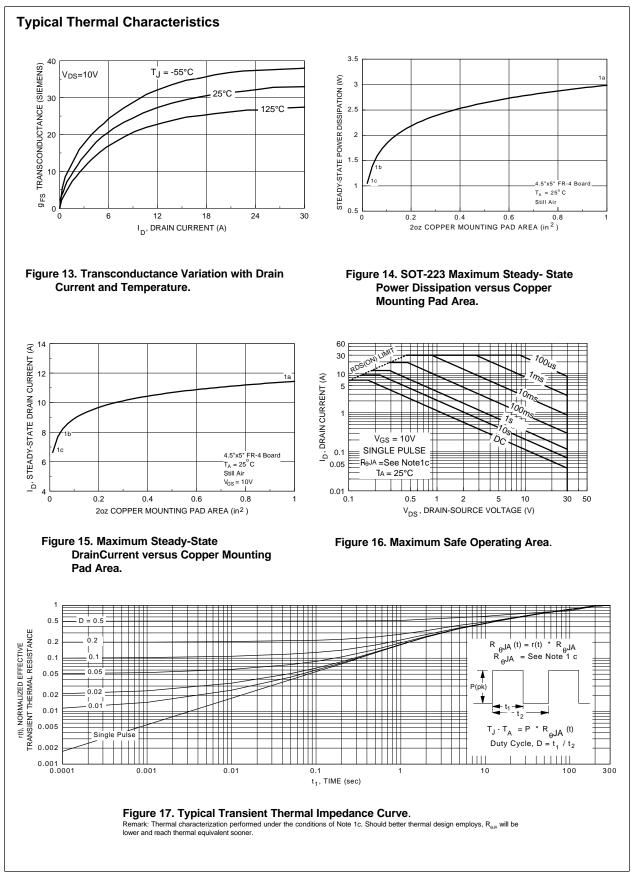
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



NDT455N Rev.F





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